

MT8372N5

30V Complementary Power MOSFET

Features

- N-Channel
30V/17A,
 $R_{DS(ON)}=20m\Omega$ @ $V_{GS}=10V$
 $R_{DS(ON)}=30m\Omega$ @ $V_{GS}=4.5V$
- P-Channel
-30V/-15A,
 $R_{DS(ON)}=25m\Omega$ @ $V_{GS}=10V$
 $R_{DS(ON)}=37m\Omega$ @ $V_{GS}=4.5V$
- RoHS Compliant

General Description

This complementary MOSFET device is produced using Mos-tech's advanced PowerTrench process that has been especially tailored to minimize the on-state resistance and yet maintain low gate charge for superior switching performance.

Applications

- DC-DC converter
- Power management
- LCD backlight inverter

Absolute Maximum Ratings

$T_A = 25^\circ\text{C}$ unless otherwise noted

Symbol	Parameter	N-CH	P-CH	Units
V _{DSS}	Drain-Source Voltage	30	-30	V
V _{GSS}	Gate-Source Voltage	±20	±20	V
I _D	Drain Current - Continuous			

Thermal Characteristics

$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient (Note 1a)	79	$^\circ\text{C/W}$
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case (Note 1)	41	$^\circ\text{C/W}$

Package Marking and Ordering Information

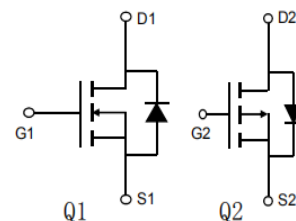
Device Marking	Device	Reel Size	Tape width	Quantity
MT8372N5	MT8372N5	13 inch	12mm	5000units



MT Semiconductor®

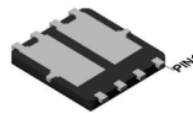
<http://www.mtsemi.com>

Simplified Schematic

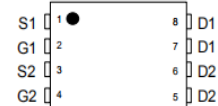


MARKING DIAGRAM & PIN ASSIGNMENT

DFN5X6-8L



Top View



Electrical Characteristics $T_A = 25^\circ\text{C}$ unless otherwise noted

Symbol	Parameter	Test Conditions	Type	Min	Typ	Max	Units
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Drain-Source Avalanche Ratings (Note 1)

W_{DSS}	Single Pulse Drain-Source Avalanche Energy	$V_{DD} = 30\text{ V}, I_D = 4.5\text{ A}$	N-CH			17	mJ
I_{AR}	Maximum Drain-Source Avalanche Current		N-CH			17	A

Off Characteristics

BV_{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0\text{ V}, I_D = 250\text{ }\mu\text{A}$ $V_{GS} = 0\text{ V}, I_D = -250\text{ }\mu\text{A}$	N-CH P-CH	30 -30			V
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	$I_D = 250\text{ }\mu\text{A}$, Referenced to 25°C $I_D = -250\text{ }\mu\text{A}$, Referenced to 25°C	N-CH P-CH		59 -47		mV/ $^\circ\text{C}$
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 24\text{ V}, V_{GS} = 0\text{ V}$ $V_{DS} = -24\text{ V}, V_{GS} = 0\text{ V}$	N-CH P-CH			1 -1	μA
I_{GSS}	Gate-Body Leakage	$V_{GS} = \pm 20\text{ V}, V_{DS} = 0\text{ V}$ $V_{GS} = \pm 20\text{ V}, V_{DS} = 0\text{ V}$	N-CH P-CH			± 100 ± 100	nA

On Characteristics (Note 2)

$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250\text{ }\mu\text{A}$ $V_{DS} = V_{GS}, I_D = -250\text{ }\mu\text{A}$	N-CH P-CH	1 -1	1.7 -1.5	2.5 -2.4	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate Threshold Voltage Temperature Coefficient	$I_D = 250\text{ }\mu\text{A}$, Referenced to 25°C $I_D = -250\text{ }\mu\text{A}$, Referenced to 25°C	N-CH P-CH		-5.6 4		mV/ $^\circ\text{C}$
$R_{DS(on)}$	Static Drain-Source On-Resistance	$V_{GS} = 10\text{ V}, I_D = 3.0\text{ A}$ $V_{GS} = 4.5\text{ V}, I_D = 2.0\text{ A}$	N-CH		20 30	25 42	m Ω
		$V_{GS} = -10\text{ V}, I_D = -3.0\text{ A}$ $V_{GS} = -4.5\text{ V}, I_D = -2.0\text{ A}$	P-CH		25 37	34 54	
$I_{D(on)}$	On-State Drain Current	$V_{GS} = 10\text{ V}, V_{DS} = 5\text{ V}$ $V_{GS} = -10\text{ V}, V_{DS} = -5\text{ V}$	N-CH P-CH	17 -15			A
g_{FS}	Forward Transconductance	$V_{DS} = 10\text{ V}, I_D = 4.5\text{ A}$ $V_{DS} = -5\text{ V}, I_D = -3.5\text{ A}$	N-CH P-CH		17 10		S

Dynamic Characteristics

C_{iss}	Input Capacitance	N-CH $V_{DS} = 25\text{ V}, V_{GS} = 0\text{ V},$ $f = 1.0\text{ MHz}$	N-CH P-CH		690 780		pF
C_{oss}	Output Capacitance	P-CH	N-CH P-CH		88 94		pF
C_{rss}	Reverse Transfer Capacitance	$V_{DS} = -25\text{ V}, V_{GS} = 0\text{ V},$ $f = 1.0\text{ MHz}$	N-CH P-CH		40 38		pF

Switching Characteristics (Note 2)

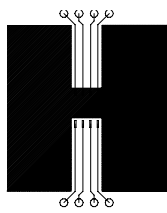
$t_{d(on)}$	Turn-On Delay Time	N-CH $V_{DD} = 30\text{ V}, I_D = 1\text{ A},$ $V_{GS} = 10\text{ V}, R_{GEN} = 6\text{ }\Omega$	N-CH P-CH		13 7	23 17	ns
t_r	Turn-On Rise Time		N-CH P-CH		8 14	19 23	ns
$t_{d(off)}$	Turn-Off Delay Time	P-CH $V_{DD} = -30\text{ V}, I_D = -1\text{ A},$ $V_{GS} = -10\text{ V}, R_{GEN} = 6\text{ }\Omega$	N-CH P-CH		19 20	39 37	ns
t_f	Turn-Off Fall Time		N-CH P-CH		6 12	17 25	ns
Q_g	Total Gate Charge	N-CH $V_{DS} = 30\text{ V}, I_D = 4.5\text{ A}, V_{GS} = 10\text{ V}$	N-CH P-CH		15.5 18	21 25	nC
Q_{gs}	Gate-Source Charge	P-CH	N-CH P-CH		2.6 2.7		nC
Q_{gd}	Gate-Drain Charge	$V_{DS} = -30\text{ V}, I_D = -3.5\text{ A}, V_{GS} = -10\text{ V}$	N-CH P-CH		2.7 3.3		nC

Electrical Characteristics (continued) $T_A = 25^\circ\text{C}$ unless otherwise noted

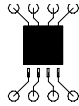
Symbol	Parameter	Test Conditions	Type	Min	Typ	Max	Units
Drain-Source Diode Characteristics and Maximum Ratings							
I_S	Maximum Continuous Drain-Source Diode Forward Current		N-CH P-CH			1.3 -1.3	A
V_{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0\text{ V}, I_S = 1.3\text{ A}$ (Note 2) $V_{GS} = 0\text{ V}, I_S = -1.3\text{ A}$ (Note 2)	N-CH P-CH		0.8 -0.8	1.1 -1.1	V

Notes:

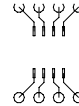
1. $R_{\theta JA}$ is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. $R_{\theta JC}$ is guaranteed by design while $R_{\theta CA}$ is determined by the user's board design.



a) 78°C/W when mounted on a 0.5 in² pad of 2 oz copper



b) 125°C/W when mounted on a .02 in² pad of 2 oz copper



c) 135°C/W when mounted on a minimum pad.

Scale 1 : 1 on letter size paper

2. Pulse Test: Pulse Width < 300μs, Duty Cycle < 2.0%

Typical Characteristics: P-CH

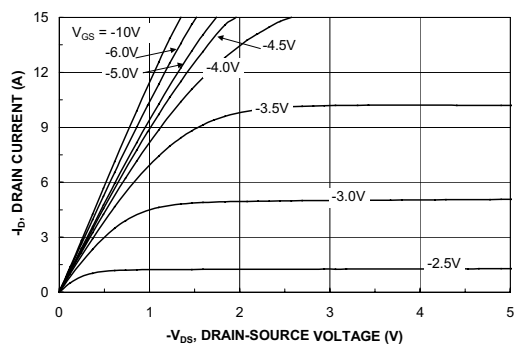


Figure 1. On-Region Characteristics.

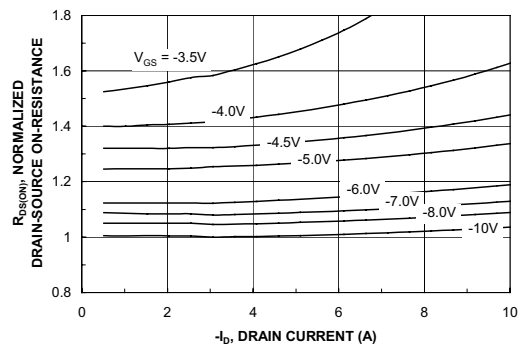


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

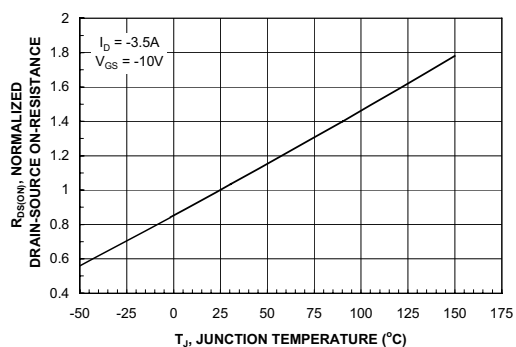


Figure 3. On-Resistance Variation with Temperature.

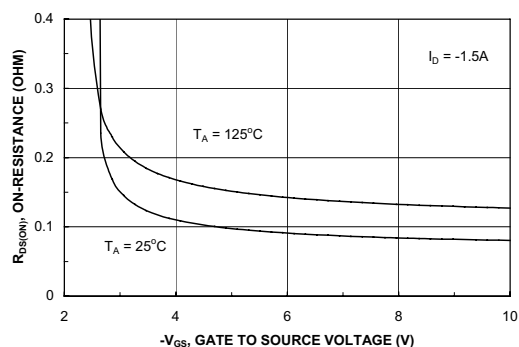


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

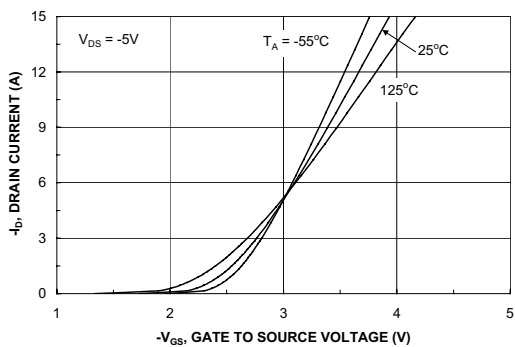


Figure 5. Transfer Characteristics.

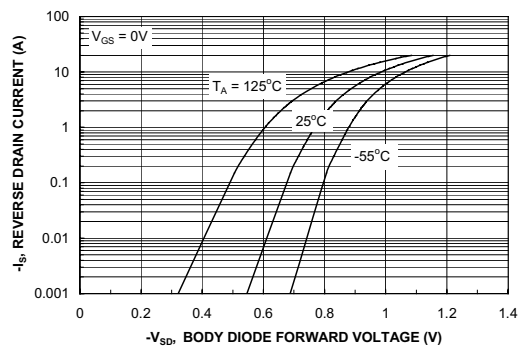


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

Typical Characteristics: P-CH

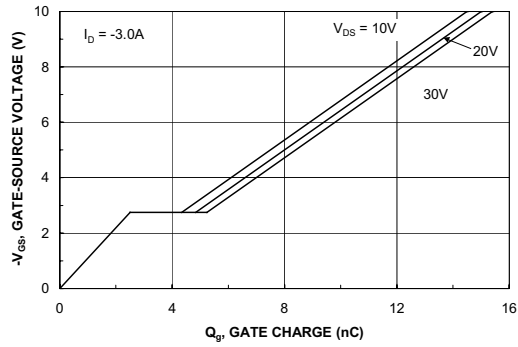


Figure 7. Gate Charge Characteristics.

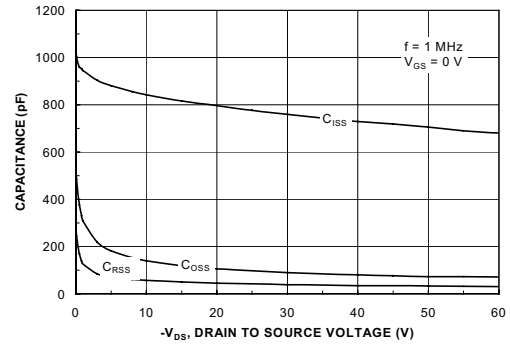


Figure 8. Capacitance Characteristics.

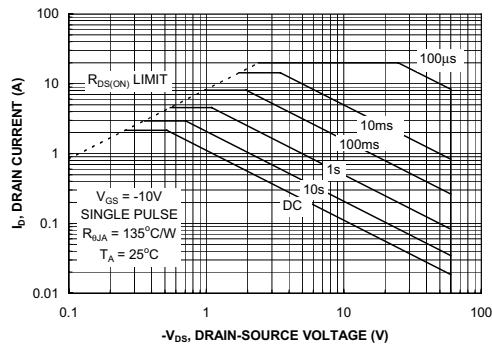


Figure 9. Maximum Safe Operating Area.

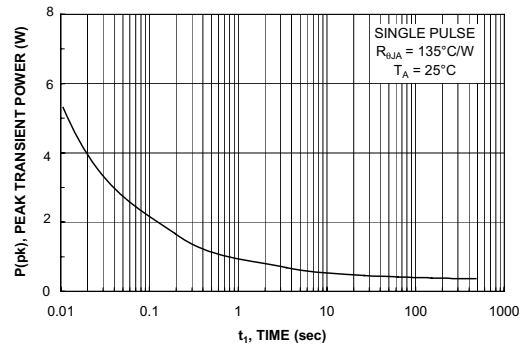


Figure 10. Single Pulse Maximum Power Dissipation.

Typical Characteristics: N-CH

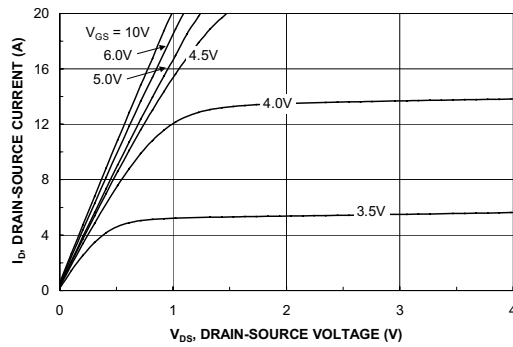


Figure 11. On-Region Characteristics.

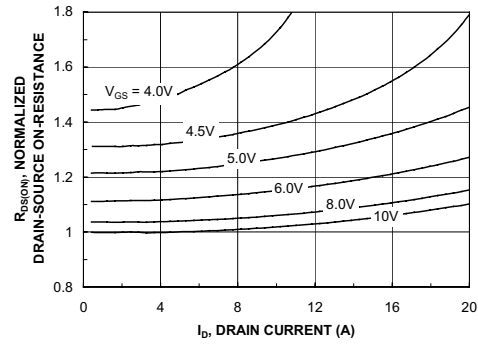


Figure 12. On-Resistance Variation with Drain Current and Gate Voltage.

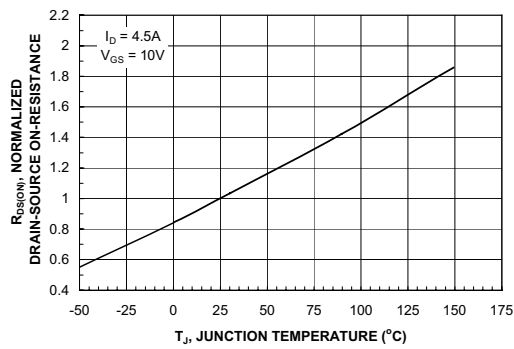


Figure 13. On-Resistance Variation with Temperature.

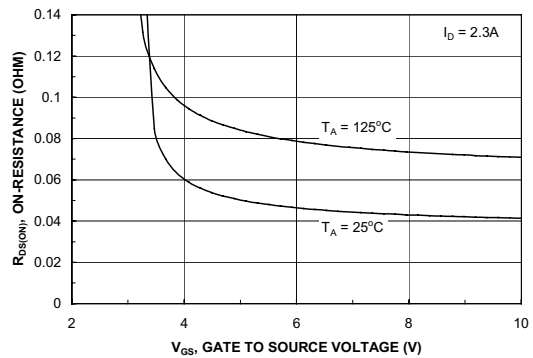


Figure 14. On-Resistance Variation with Gate-to-Source Voltage.

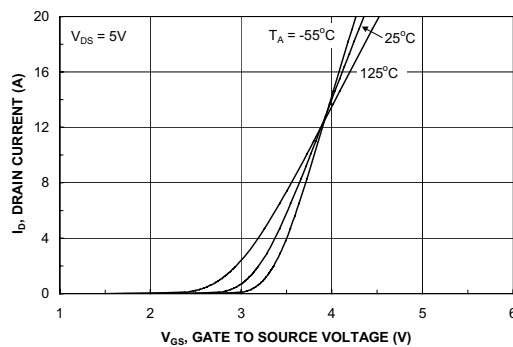


Figure 15. Transfer Characteristics.

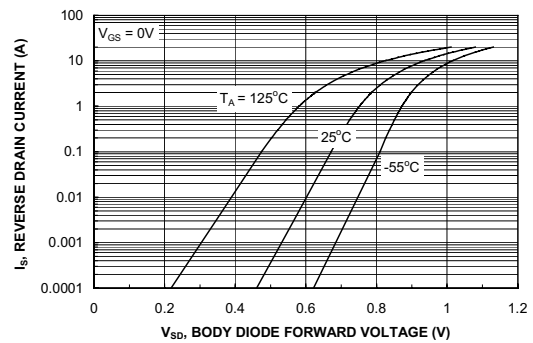


Figure 16. Body Diode Forward Voltage Variation with Source Current and Temperature.

Typical Characteristics: N-CH

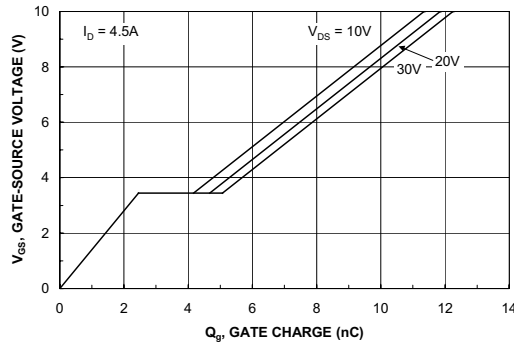


Figure 17. Gate Charge Characteristics.

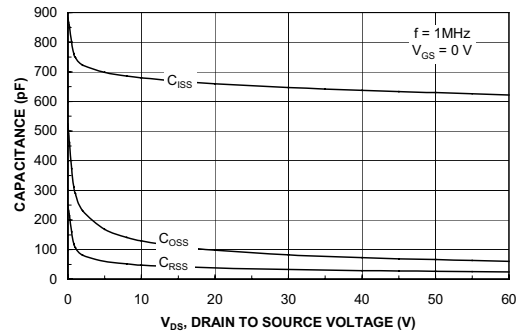


Figure 18. Capacitance Characteristics.

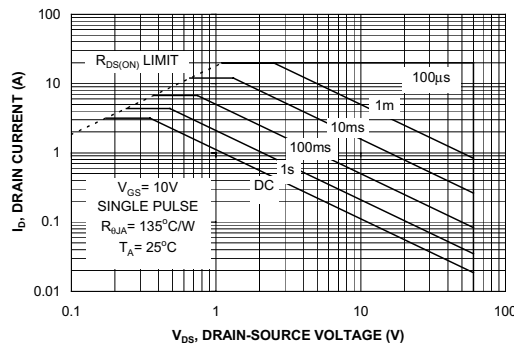


Figure 19. Maximum Safe Operating Area.

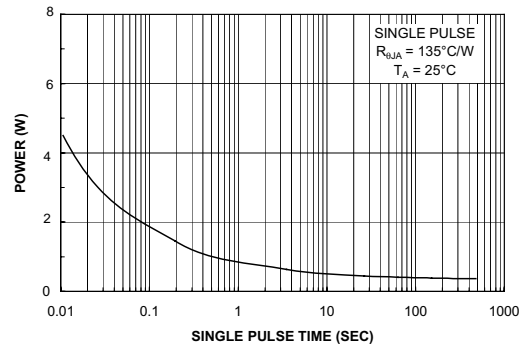


Figure 20. Single Pulse Maximum Power Dissipation.

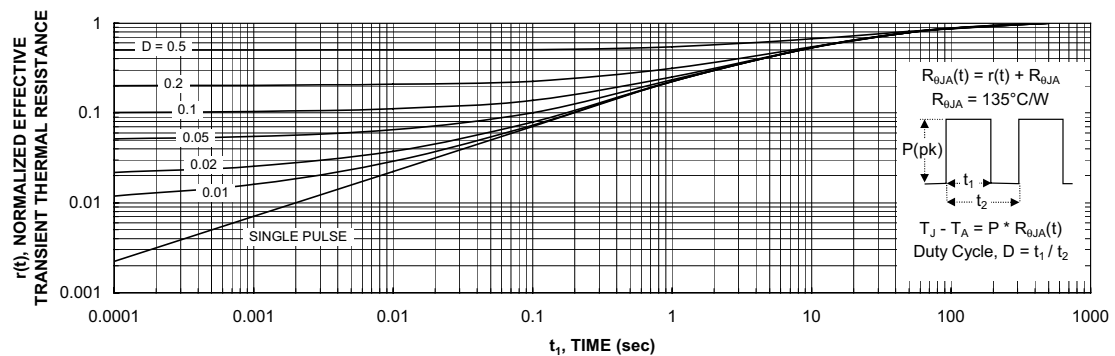
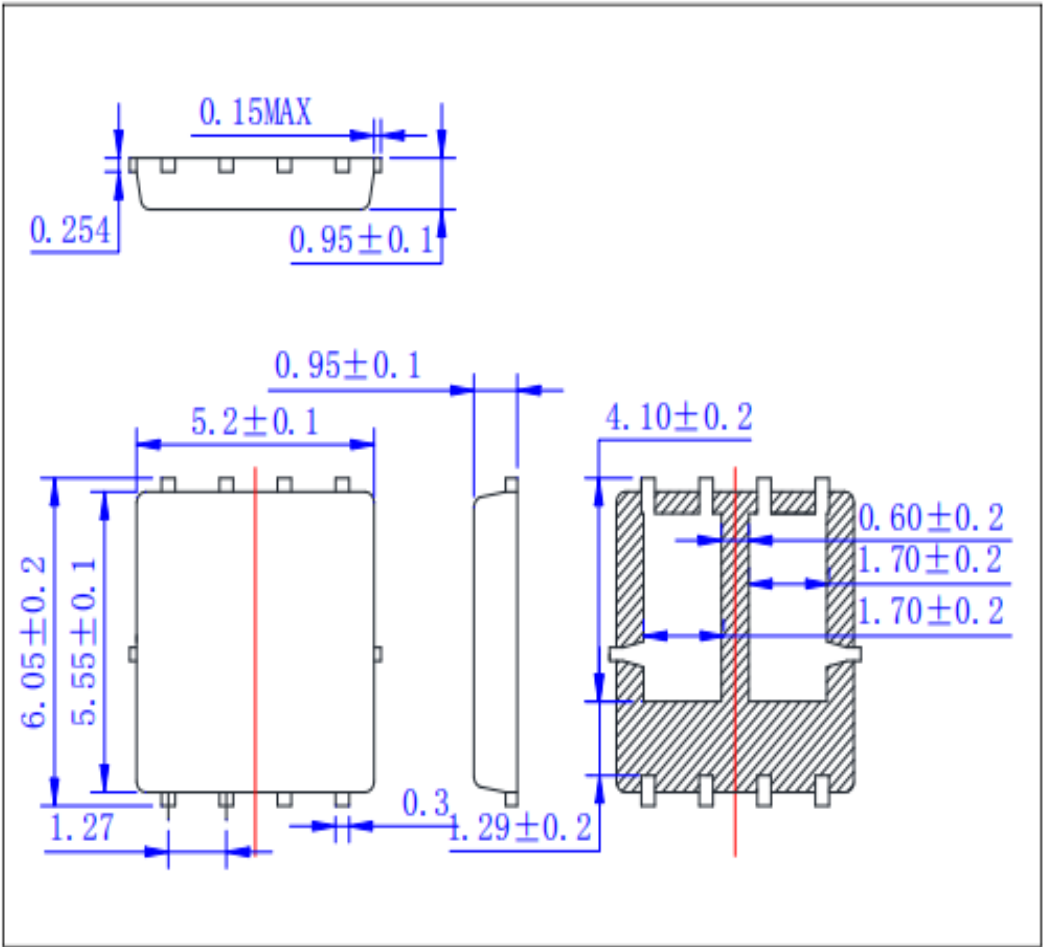


Figure 21. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1c.
Transient thermal response will change depending on the circuit board design.

DFN5×6 OUTLINE



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Keep safety first in your circuit designs!

1. MOS-TECH Semiconductor Corp. puts the maximum effort into making semiconductor products better and more reliable, but there is always the possibility that trouble may occur with them. Trouble with semiconductors may lead to personal injury, fire or property damage.
Remember to give due consideration to safety when making your circuit designs, with appropriate measures such as (i) placement of substitutive, auxiliary circuits, (ii) use of nonflammable material or (iii) prevention against any malfunction or mishap.